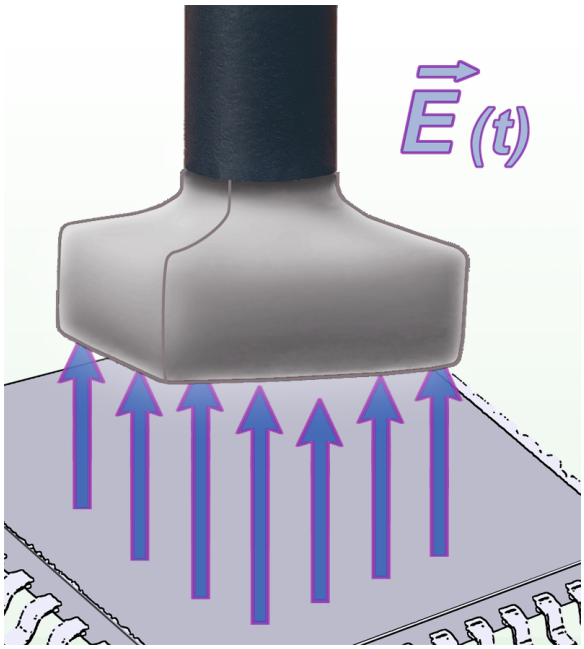
# XFS-E 09s

## Scanner Probe 30 MHz up to 6 GHz




### Short description

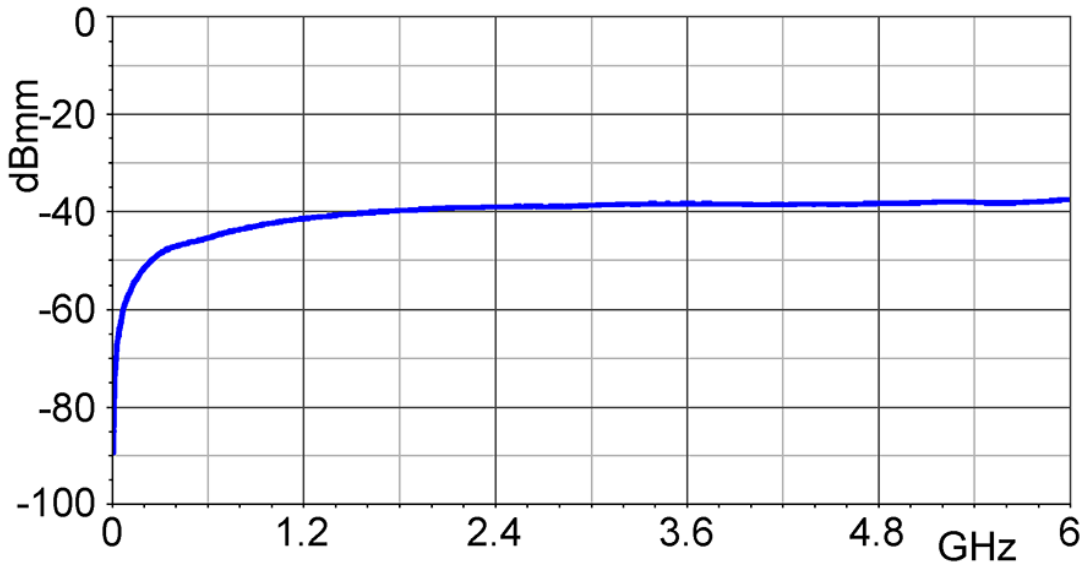
The electrode on the probe head of the XFS-E 09s scanner probe detects electrical fields which, for example are decoupled above the IC's surface. The probe's resolution allows for measurements with a distance of 0.5 mm to 10 mm above an assembly. For measurement, the E-field probe is placed on the target.

The XSF-E 09s is a passive near-field probe. To measure, the E-field probe is positioned above or onto components and printed circuit boards. It has a current attenuating sheath and, therefore, its upper half is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E-field scanner probe has an internal terminating resistance.

### Technical parameters

| | |
|---|---|
| **Frequency range** | 30 MHz ... 6 GHz |
| **Resolution** | ≈ 0.2 mm |
| **Probe head dimensions** | ≈ (10 x 10) mm |
| **Connector - output** | SMA, male, jack |

Frequency response [dBµV] / [dBµA/m]

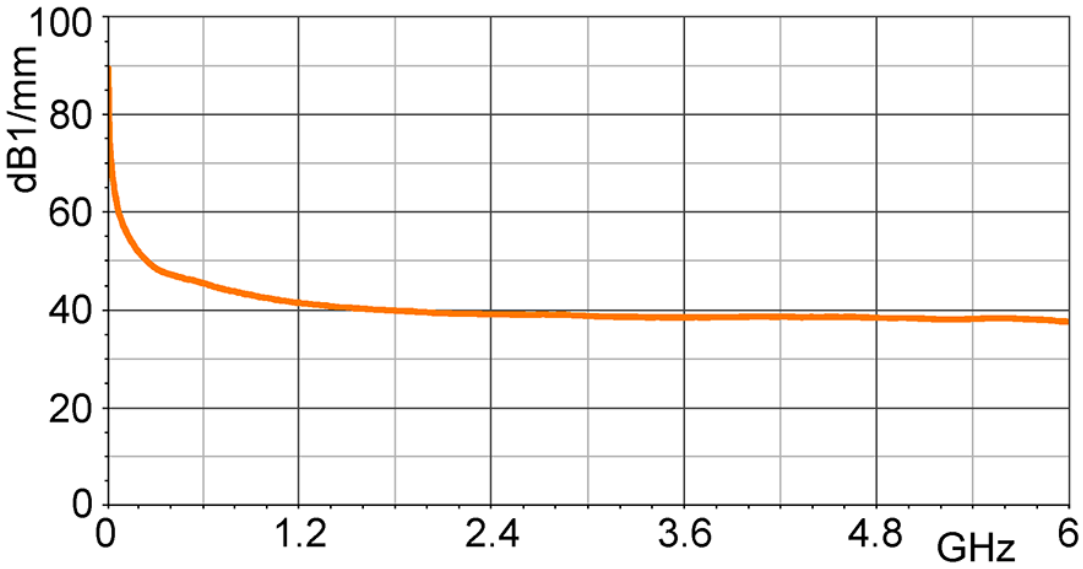



Sales Partner:

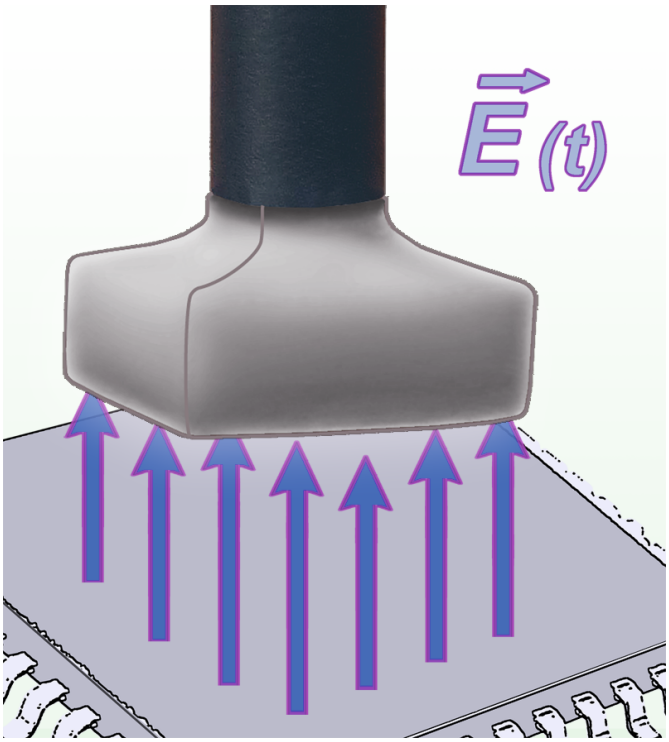
ABSOLUTE EMC Llc.
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E- field correction curve [dBµV/mm] / [dBµV]




Measuring principles



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